

Supporting Information

Synergistic Heterojunction of SnS₂/SnSSe Nanosheets on GaN for Advanced Self-powered Photodetectors

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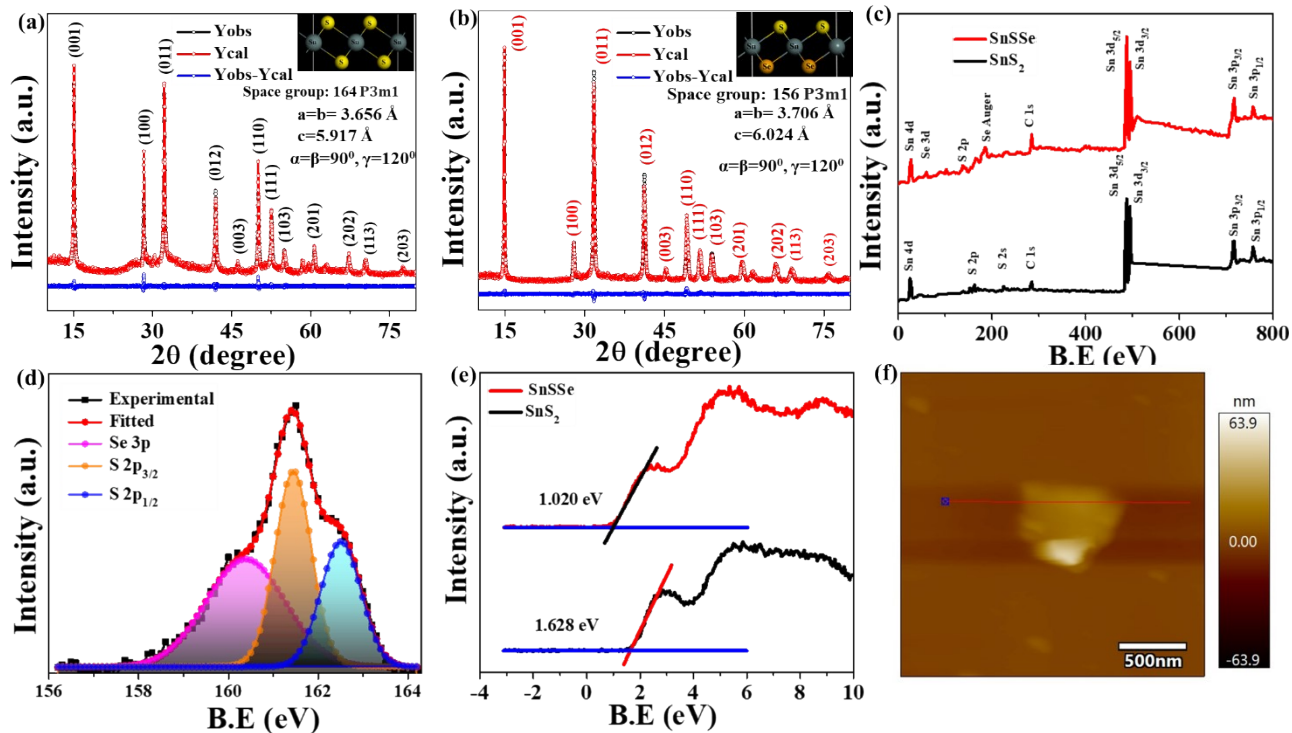


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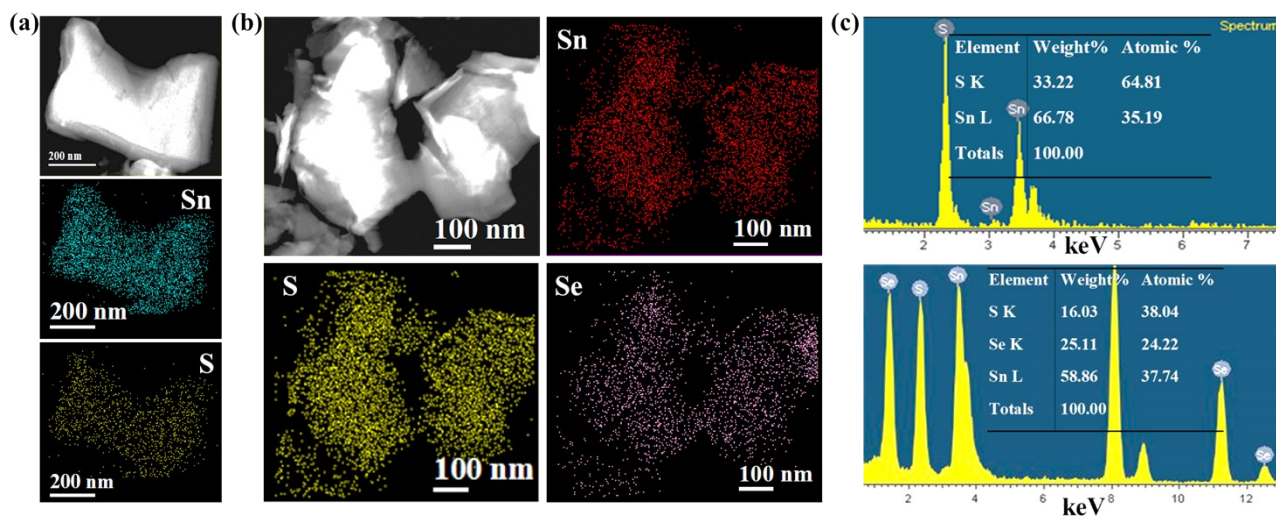


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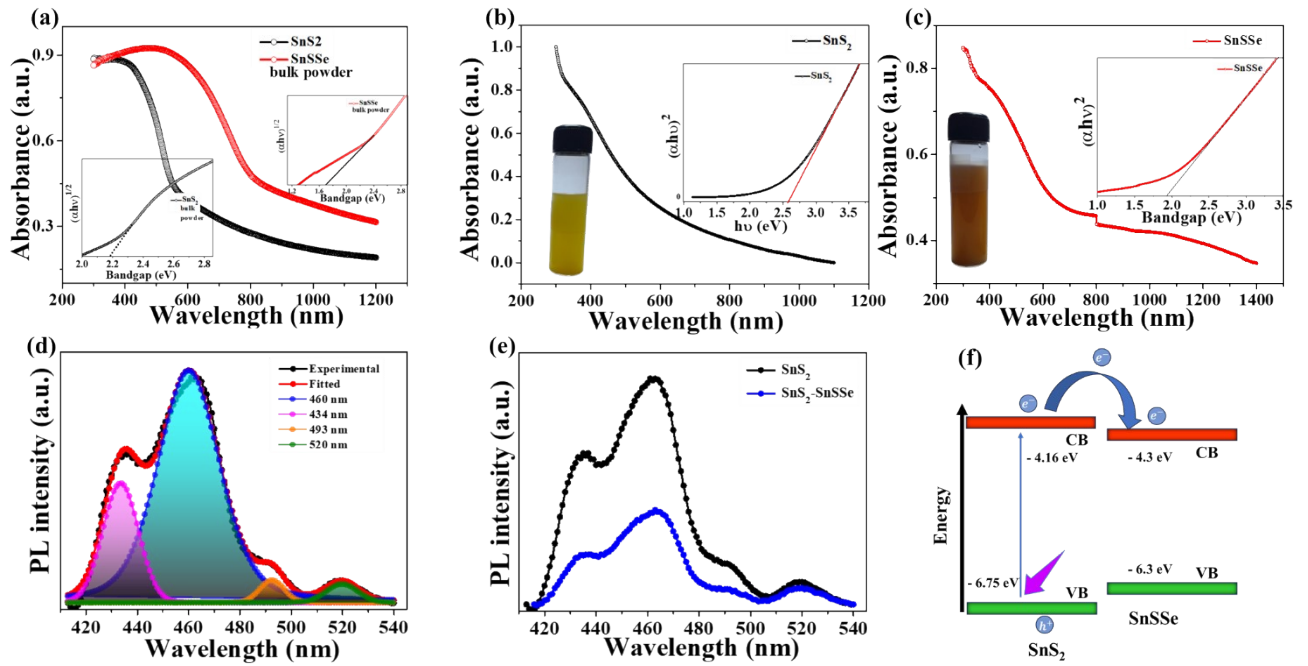


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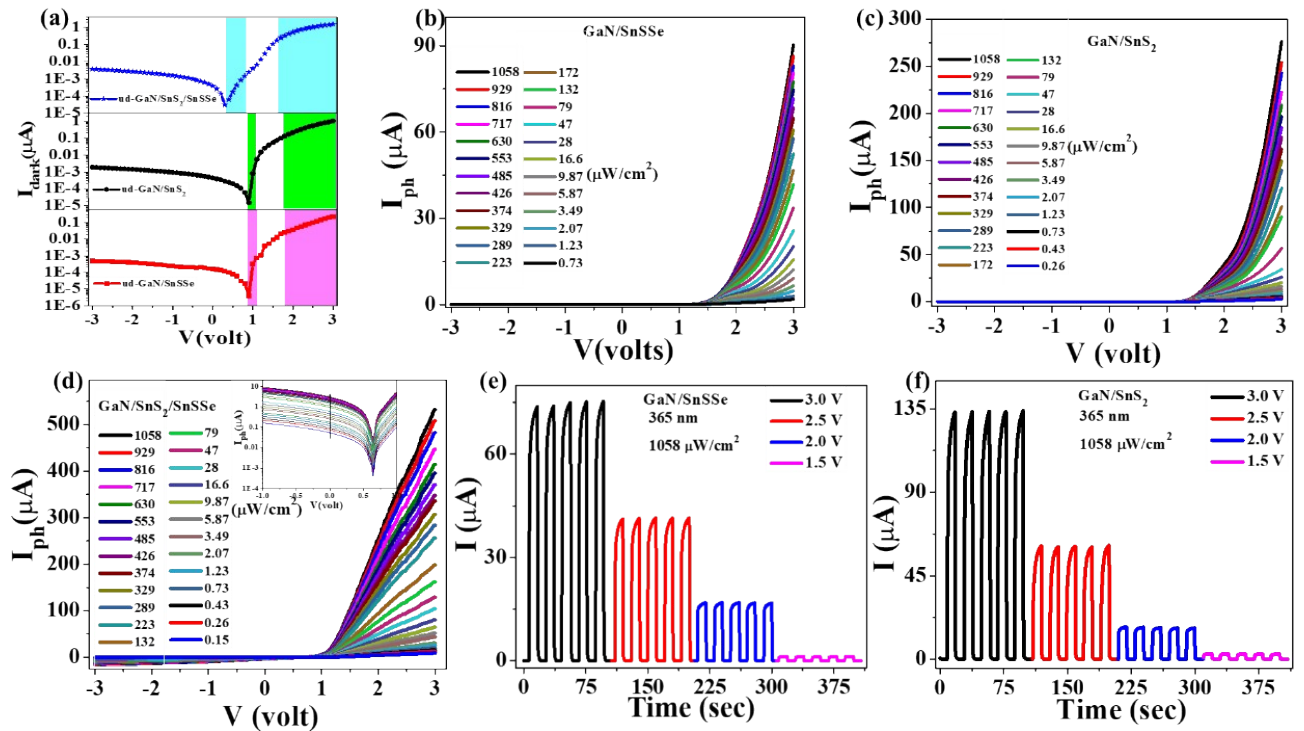


Figure. S4. (a) semi-logarithmic I-V curves of the fabricated devices, (b)- (c) Photoresponse recorded with varying intensity under 365 nm illumination, (e)-(f) Bias Photoresponse recorded with varying intensity under 365 nm illumination.

dependent photo switching of the device D₁ and D₂ at fixed intensity of 1058 $\mu\text{W}/\text{cm}^2$.

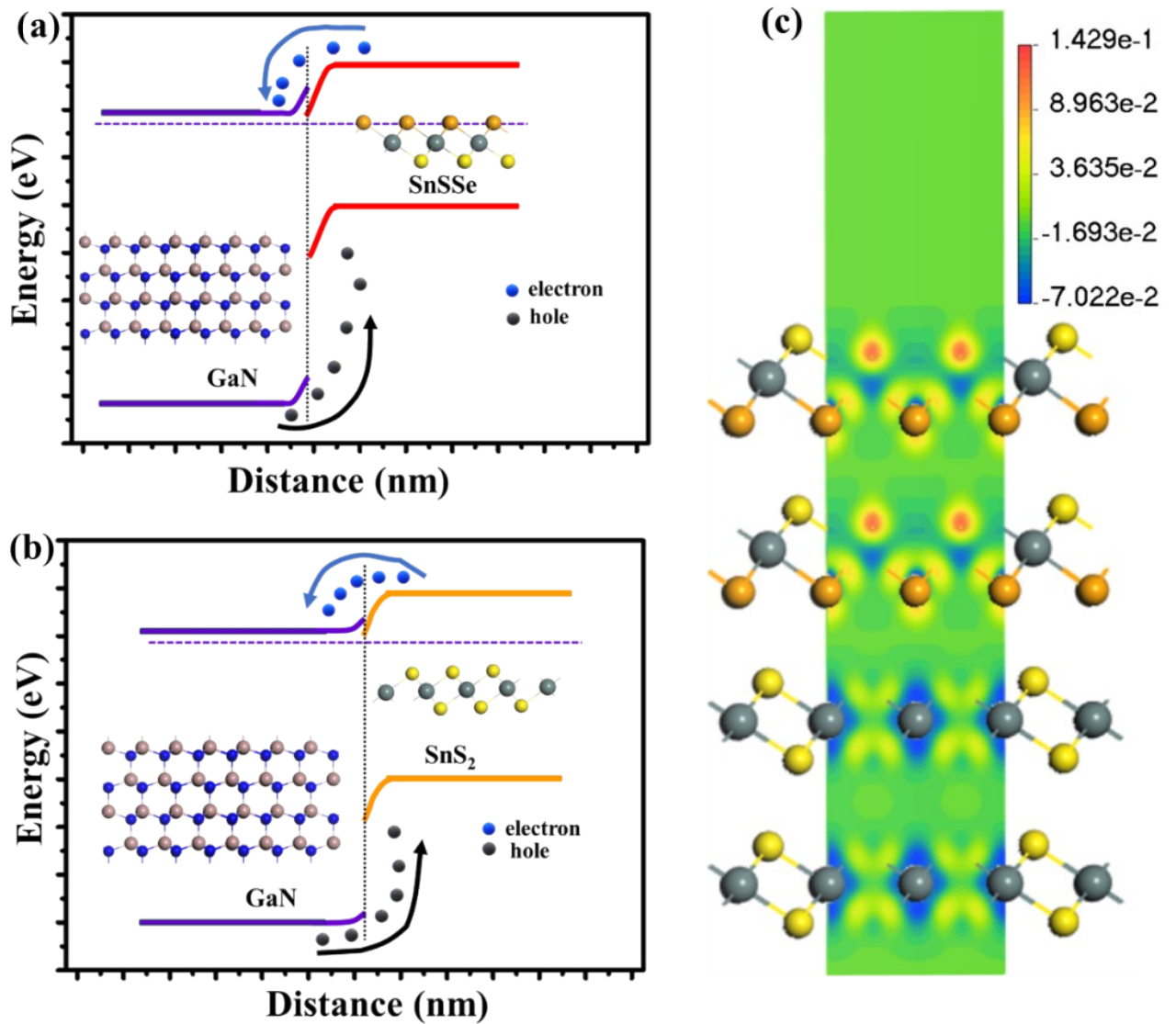


Figure. S5. (a), (b) Schematics of energy band diagram for D₁ and D₂ device configuration, (c) Simulated electron density distribution of SnS₂/SnSSe heterostructure.

Table ST1. Parameters to calculate the average photoluminescence lifetime of carriers

$$T = A + B_1 * \exp(-i/T_1) + B_2 * \exp(i/T_2)$$

Sample	Excitation (nm)	Emission (nm)	Average life time (ns)	T ₁ (ns)	T ₂ (ns)	B ₁	B ₂
SnS ₂			2.629	0.914461	6.04562	66.57	33.43
	375	460					
SnS ₂ - SnSSe			1.483	0.900447	5.2463	86.59	13.41

Table ST2. Parameters to calculate the average photoluminescence lifetime of carriers.

$$T = A + B_1 * \exp(-i/T_1) + B_2 * \exp(i/T_2)$$

Device configuration	Excitation (nm)	Emission (nm)	Average life time (ns)	T ₁ (ns)	T ₂ (ns)	B ₁	B ₂
GaN/SnS ₂			6.692	0.52091	7.36049	9.76	90.23
GaN/SnSSe	375	460	6.603	0.29676	7.25718	9.39	90.60
GaN/SnS ₂ /SnSSe			4.931	0.71218	7.37601	36.69	63.31

Table ST3. Performance comparison of our fabricated device with other reported work.

Device configuration	Wavelength (nm)	Bias (volt)	R (A/W)	EQE (%)	D* (Jones)	Refer.
CTS QDs/SnS ₂	320	5	53.88	20,878	3.2 × 10 ¹³	1
SnS ₂ /ITO	405	3	58 × 10 ⁻³	17.9	1.53 × 10 ¹⁰	2
Cr: Au/SnS ₂ /Cr: Au	365	1	112	3.7 × 10 ⁴	1.18 × 10 ¹¹	3
Ag/SnS ₂ /Ag	365	5	5.5	1868	1.72 × 10 ¹³	4
Si/SnS ₂	405	-2	0.12		9.35 × 10 ¹⁰	5
SnS ₂ /Si NW	340	2	100	3.64 × 10 ₄	1.14 × 10 ¹⁴	6
Au/In-SnS ₂ /Au	405	5	153.8	4.72 × 10 ₄	5.81 × 10 ¹²	7
SnS ₂ /PEDOT: PSS	300	-1	182.89	7.55 × 10 ₄	1.44 × 10 ¹²	8
Al/SnS ₂ /CuO/ PEDOT: PSS/ITO	300	-1	1.87	775.41	1.10 × 10 ¹¹	9
SnS ₂ /Ag ₂ S	405	2	4.52		3.53 × 10 ¹¹	10
SnS ₂ /GaN	265	0	3.52		1.76 × 10 ¹⁴	11
p-Si/SnS ₂	365	0	0.0125		2.85 × 10 ⁷	12
InSe/SnS ₂ /GeSe	355	0	1.87	656	8.39 × 10 ¹²	13
SnO ₂ /In ₂ O ₃ /SnS ₂	555	0	2.9 × 10 ⁻³		5.9 × 10 ⁷	14
ITO/SnS ₂ /ZnO _{1-x} S _x /Au	365	0	8.28 × 10 ⁻³		5.09 × 10 ¹⁰	15
Ud-GaN/SnS ₂ /SnSSe	365	3	314.96	10.7 × 10 ₄	2.00 × 10 ¹⁴	This work
		0	1.52	519	6.06 × 10 ¹³	

Table ST4. Population analysis (Mulliken and Hirshfeld) for geometry optimized SnS₂.

Atomic Populations (Mulliken)								Hirshfeld Analysis		
Species	Ion	s	p	d	f	Total	Charge (e)	Species	Ion	Hirshfeld Charge (e)
S	1	1.89	4.57	0.00	0.00	6.46	-0.46	S	1	-0.14
S	2	1.89	4.57	0.00	0.00	6.46	-0.46	S	2	-0.14
Sn	1	1.16	1.92	0.00	0.00	3.08	0.92	Sn	1	0.28

Table ST5. Population analysis (Mulliken and Hirshfeld) for geometry optimized SnSSe.

Atomic Populations (Mulliken)								Hirshfeld Analysis		
Species	Ion	s	p	d	f	Total	Charge (e)	Species	Ion	Hirshfeld Charge (e)
S	1	1.90	4.56	0.00	0.00	6.46	-0.46	S	1	-0.15
Se	1	1.79	4.45	0.00	0.00	6.24	-0.24	Se	1	-0.11
Sn	1	1.31	1.99	0.00	0.00	3.30	0.70	Sn	1	0.26

Table ST6. Population analysis for SnS₂/ SnSSe heterostructures.

Atomic Populations (Mulliken)							Hirshfeld Analysis			
Species	Ion	s	p	d	f	Total Charge (e)	Species	Ion	Hirshfeld Charge (e)	
S	1	1.89	4.56	0.00	0.00	6.46	-0.46	S	1	-0.14
S	2	1.90	4.56	0.00	0.00	6.46	-0.46	S	2	-0.14
S	3	1.90	4.55	0.00	0.00	6.45	-0.45	S	3	-0.15
S	4	1.90	4.56	0.00	0.00	6.45	-0.45	S	4	-0.14
S	5	1.89	4.57	0.00	0.00	6.47	-0.47	S	5	-0.15
S	6	1.89	4.57	0.00	0.00	6.47	-0.47	S	6	-0.15
Se	1	1.75	4.45	0.00	0.00	6.21	-0.21	Se	1	-0.11
Se	2	1.81	4.45	0.00	0.00	6.26	-0.26	Se	2	-0.11
Sn	1	1.18	1.91	0.00	0.00	3.09	0.91	Sn	1	0.29
Sn	2	1.18	1.90	0.00	0.00	3.08	0.92	Sn	2	0.29
Sn	3	1.31	2.01	0.00	0.00	3.32	0.68	Sn	3	0.25
Sn	4	1.27	2.01	0.00	0.00	3.27	0.73	Sn	4	0.25

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